

<b>Notice of References Cited</b>	Application/Control No. 10/599,713		Applicant(s)/Patent Under Reexamination KRUSE ET AL.	
	Examiner JD SCHULTZ, PhD		Art Unit 1633	Page 1 of 1

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*	B	US-2004/0037813	02-2004	Simpson et al.	424/93.7
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	L	US-			
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	U	Kruse et al. Appl. Phys. A, 2004. 79:1617-1624
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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